

Search Notes

Application/Control No.

10/748,200

Examiner

Patricia T. Nguyen

Applicant(s)/Patent under
Reexamination

NAIR ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	51	5/3/2005	PN
//	258	//	/

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
330	51	5/3/2005	PN
//	258	//	//

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR